



Contribution ID: 248

Type: Poster

## The Nothing On Insulator Nanotransistor with Diamond Lateral Islands for Electrons Emission in Vacuum

Wednesday 20 June 2018 18:00 (20 minutes)

**Abstract:** A diamond on insulator structure with a pure tunnelling conduction between source and drain, modulated by a gate bias, is investigated as alternative nano-device. The Nothing On Insulator (NOI) cavity represents the main device body. The Atlas simulations establish superior drain currents and minimum capacitances suitable for THz operation.

**Introduction:** The NOI nano-device and the lateral field emission devices have in common the Fowler-Nordheim tunnelling; its distinctive features are the nano-diamond islands sizes and a cavity of only 1...4nm, so suitable for co-integration with Diamond/Si-FETs. Also, the dynamic study is a novelty for this device.

**Methods:** In the first set of simulations the diamond islands have flat walls of 15nmx15nm on insulator of 15nm, a vacuum cavity of 2nm, p-type diamond doping concentration of  $NA=2E+20cm^{-3}$ , oxide/diamond interface charge. In the second set, the walls roughness is considered as 3 growths.

**Results:** The transfer characteristics reveal better ION/IOFF >108, better subthreshold slopes than Si-NOI and prove the main distinctive feature of this nano-transistor versus the lateral diamond field emission devices - the gate control of  $0.1 \div 10$  nA/V. The output characteristics obey to the exponential shape, offering superior ON voltage than Si-NOI. Due to an extremely low area, the simulated capacitances are about 0.5 ...0.06aF meaning a cutoff frequency around THz. The conductances start from 10-16S and increase toward 10-5S at 100GHz. The device with roughness improves all these features, sharp growths facilitating the tunnelling.

**Discussion:** In conclusions, the Diamond-NOI implementation versus Si-NOI offers better: gate breakdown, ON drain-source voltage, ION/IOFF, sub-500mV/dec subthreshold slopes, sub-aF capacitances suitable for THz applications.

**Acknowledgements:** Supported by grant of Ministry of Research and Innovation, CNCS - UEFISCDI, project number PN-III-P4-ID-PCE-2016-0480, nr 4/2017.

**Author:** Mr TOPOR, Alexandru (UPB-Romania)

**Co-author:** Dr RAVARIU, Cristian (UPB-Bucharest)

**Presenter:** Mr TOPOR, Alexandru (UPB-Romania)

**Session Classification:** Poster Session Wednesday

**Track Classification:** Nanometer Structures & Nanotechnology